

October 2014
FDMS8027S

# N-Channel PowerTrench<sup>®</sup> SyncFET<sup>TM</sup> 30 V, 22 A, 5.0 m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 5.0 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 18 \text{ A}$
- Max  $r_{DS(on)} = 6.2 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 16 \text{ A}$
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- SyncFET Schottky Body Diode
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

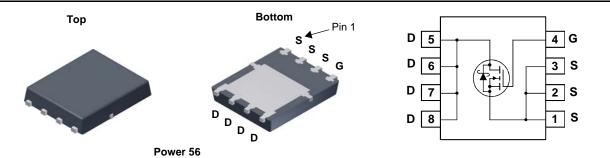


#### **General Description**

The FDMS8027S has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{\text{DS}(\text{on})}$  while maintaining excellent switching performance. This device has the added benefit of an efficient monolithic Schottky body diode.

# **Applications**

- Synchronous Rectifier for DC/DC Converters
- Notebook Vcore/GPU low side switch
- Networking Point of Load low side switch
- Telecom secondary side rectification



# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
$V_{DS}$	Drain to Source Voltage			30	V	
$V_{GS}$	Gate to Source Voltage		(Note 4)	±20	V	
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25°C		22		
	-Continuous (Silicon limited)	T <sub>C</sub> = 25°C		70	Α	
'D	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	18	^	
	-Pulsed			100		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	33	mJ	
<b>D</b>	Power Dissipation	T <sub>C</sub> = 25°C		36	W	
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	2.5	VV	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +150	°C	

#### **Thermal Characteristics**

$R_{ heta JC}$	Thermal Resistance, Junction to Case		3.4	°C/W
R <sub>a IA</sub>	Thermal Resistance, Junction to Ambient (N	lote 1a)	50	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8027S	FDMS8027S	Power 56	13 "	12 mm	3000 units

# **Electrical Characteristics** $T_J = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0 V	30			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25°C		18		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			500	μА
$I_{GSS}$	Gate to Source Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 1 \text{ mA}$	1.2	1.5	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25°C		-4		mV/°C
r <sub>DS(on)</sub>		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 18 A		4.2	5.0	
	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 16 \text{ A}$		5.4	6.2	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 18 \text{ A}, T_J = 125^{\circ}\text{C}$		5.3	6.8	
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V, } I_{D} = 18 \text{ A}$		92		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45 V V 0 V	1365	1815	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1MHz	550	730	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	T = 1MHZ	70	105	pF
$R_g$	Gate Resistance		0.5	2.5	Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		10	19	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 18 A,	2.3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	25	40	ns
t <sub>f</sub>	Fall Time		6	12	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	23	31	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V} V_{DD} = 15 \text{ V},$	11	16	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = 18 A	3.3		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		3.7		nC

#### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source-Drain Dioge Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2 \text{ A}$ (Note 2)	0.63	0.8	V
		$V_{GS} = 0 \text{ V}, I_S = 18 \text{ A}$ (Note 2)	0.8	1.2	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 18 A, di/dt = 300 A/μs	23	36	ns
Q <sub>rr</sub>	Reverse Recovery Charge	- I <sub>F</sub> = 16 A, αι/αι = 300 A/μs	20	32	nC

#### Notes

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a
 1 in<sup>2</sup> pad of 2 oz copper.



 b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu\text{s},$  Duty cycle < 2.0%.
- 3.  $E_{AS}$  of 33 mJ is based on starting  $T_J$  = 25 °C, L = 0.3 mH,  $I_{AS}$  = 15 A,  $V_{DD}$  = 27 V,  $V_{GS}$  = 10 V.
- 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied.

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

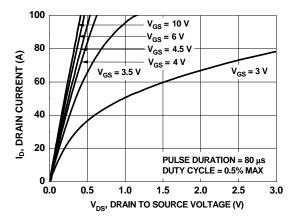


Figure 1. On Region Characteristics

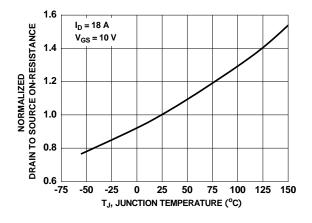


Figure 3. Normalized On Resistance vs Junction Temperature

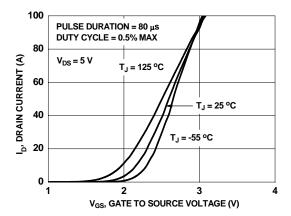


Figure 5. Transfer Characteristics

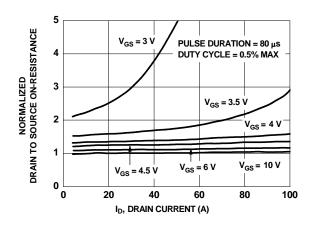


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

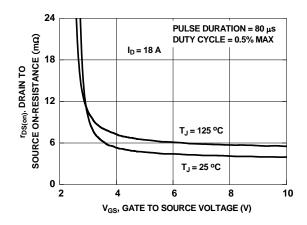


Figure 4. On-Resistance vs Gate to Source Voltage

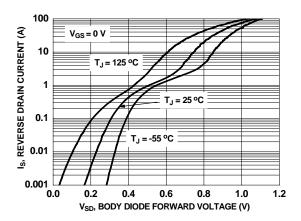


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

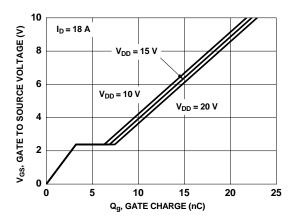


Figure 7. Gate Charge Characteristics

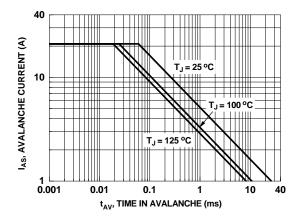


Figure 9. Unclamped Inductive Switching Capability

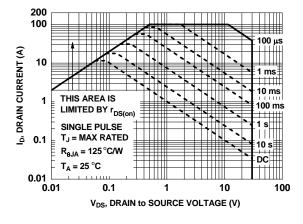


Figure 11. Forward Bias Safe Operating Area

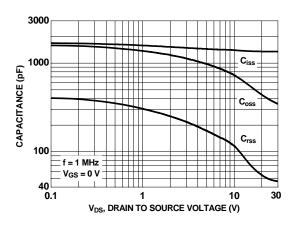


Figure 8. Capacitance vs Drain to Source Voltage

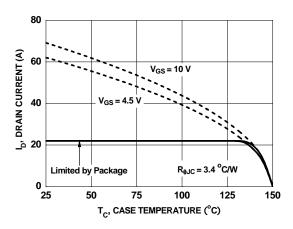


Figure 10. Maximum Continuous Drain Current vs Case Temperature

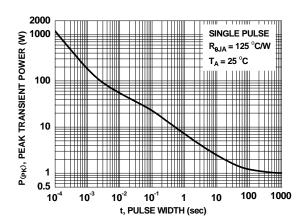


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

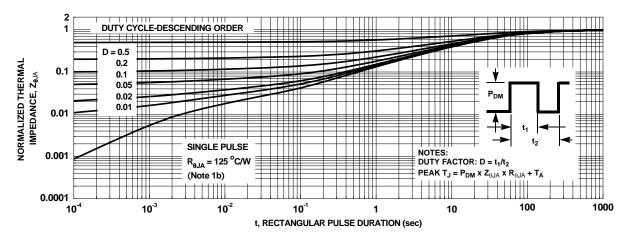


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

# Typical Characteristics (continued)

# SyncFET Schottky body diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS8027S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

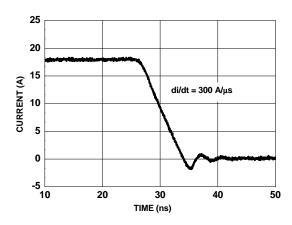


Figure 14. FDMS8027S SyncFET body diode reverse recovery characteristic

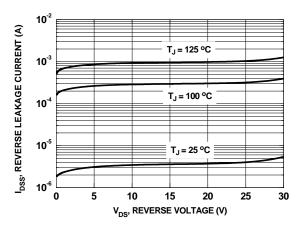


Figure 15. SyncFET body diode reverse leakage versus drain-source voltage



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